

<b>Notice of References Cited</b>	Application/Control No. 10/585,067	Applicant(s)/Patent Under Reexamination TANAKA ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0228249 A1	12-2003	Fujimura et al.	423/446
	B	US-			
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	translation of Savinkin et al. (RU 2164524 C1), 12/24/2009
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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